Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination MUMM ET AL. Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0109949	06-2003	Ikeda et al.	700/98
	В	US-5,293,479	03-1994	Quintero et al.	715/841
	С	US-2002/0052807	05-2002	Han et al.	705/27
	D	US-2003/0078975	04-2003	Ouchi, Norman Ken	709/205
	Е	US-2002/0030689	03-2002	Eichel et al.	345/588
	F	US-2004/0015367	01-2004	Nicastro et al.	705/1
	G	US-2002/0070932	06-2002	Kim, Jesse Jaejin	345/419
	н	US-2002/0138170	09-2002	Onyshkevych et al.	700/130
	1	US-2002/0035408	03-2002	Smith, Terrance W.	700/97
	J	US-2003/0078859	04-2003	Coke et al.	705/27
	К	US-2003/0067487	04-2003	Kohls et al.	345/764
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	И					
	0					
	Р					
	Q		·			
	·R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.